

SANYO Semiconductors DATA SHEET

An ON Semiconductor Company

N-Channel Silicon MOSFET

EFC4612R — General-Purpose Switching Device Applications

Features

- 2.5V drive
- · Built-in gate protection resistor
- · Best suited for LiB charging and discharging switch
- · Common-drain type
- · Halogen free compliance

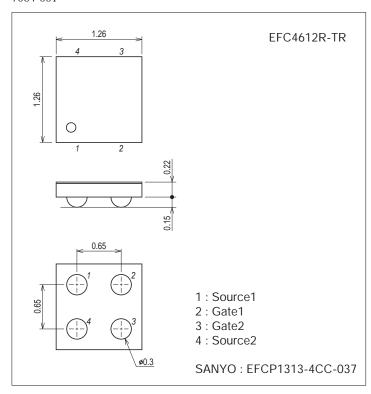
Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Source-to-Source Voltage	VSSS		24	V
Gate-to-Source Voltage	V _{GSS}		±12	V
Source Current (DC)	IS		6	А
Source Current (Pulse)	ISP	PW≤10μs, duty cycle≤1%	60	А
Total Dissipation	PT	When mounted on ceramic substrate (5000mm ² ×0.8mm)	1.6	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

Package Dimensions

unit : mm (typ) 7064-001

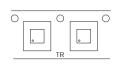


Product & Package Information

Package : EFCPJEITA, JEDEC : -

• Minimum Packing Quantity : 5,000 pcs./reel

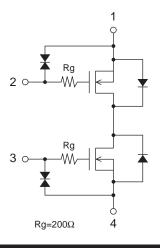
Taping Type: TR



Marking



Electrical Connection



SANYO Semiconductor Co., Ltd.

EFC4612R

Electrical Characteristics at Ta=25°C

Parameter	Cumbal	Canditions	Conditions		Ratings		
Parameter	Symbol	Conditions			typ	max	Unit
Source-to-Source Breakdown Voltage	V(BR)SSS	IS=1mA, VGS=0V Test Circuit 1		24			V
Zero-Gate Voltage Source Current	ISSS	V _{SS} =20V, V _{GS} =0V	Test Circuit 1			1	μΑ
Gate-to-Source Leakage Current	IGSS	VGS=±8V, VSS=0V	Test Circuit 2			±10	μΑ
Cutoff Voltage	VGS(off)	VSS=10V, IS=1mA	VSS=10V, IS=1mA Test Circuit 3			1.3	V
Forward Transfer Admittance	yfs	VSS=10V, IS=3A	Test Circuit 4		3.1		S
	R _{SS} (on)1	IS=3A, VGS=4.5V	Test Circuit 5	24	39	45	mΩ
	RSS(on)2	IS=3A, VGS=4.0V	Test Circuit 5	25	41	48	$m\Omega$
Static Source-to-Source On-State Resistance	RSS(on)3	I _S =3A, V _{GS} =3.7V	Test Circuit 5	27.5	43	50	mΩ
	RSS(on)4	IS=3A, VGS=3.1V	Test Circuit 5	31.5	48	57	mΩ
	RSS(on)5	IS=3A, VGS=2.5V	Test Circuit 5	33.5	58	72	mΩ
Turn-ON Delay Time	t _d (on)		Test Circuit 7		20		ns
Rise Time	t _r	See specified Test Circuit.			230		ns
Turn-OFF Delay Time	t _d (off)	See specified lest circuit.			130		ns
Fall Time	tf				210		ns
Total Gate Charge	Qg	V _{SS} =10V, V _{GS} =4.5V, I _S =6A			7		nC
Forward Source-to-Source Voltage	VF(S-S)	I _S =3A, V _{GS} =0V Test Circuit 6			0.8	1.2	V

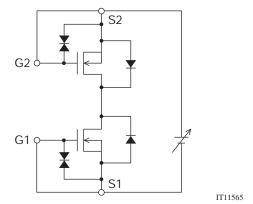
Ordering Information

Device Package		Shipping	memo	
EFC4612R-TR			Pb Free and Halogen Free	

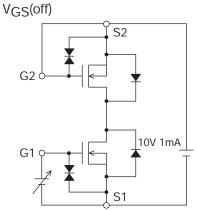
Test circuits are example of measuring FET1 side

Test Circuit 1

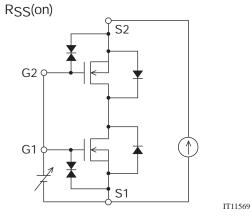
VSSS / ISSS



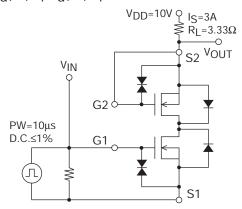
Test Circuit 3



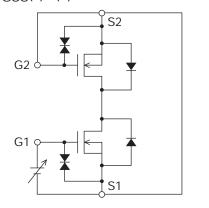
Test Circuit 5



Test Circuit 7 t_d(on), t_r, t_d(off), t_f



Test Circuit 2 IGSS(+) / (--)

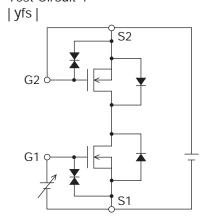


IT11566

IT11568

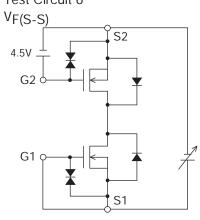
IT11570

Test Circuit 4

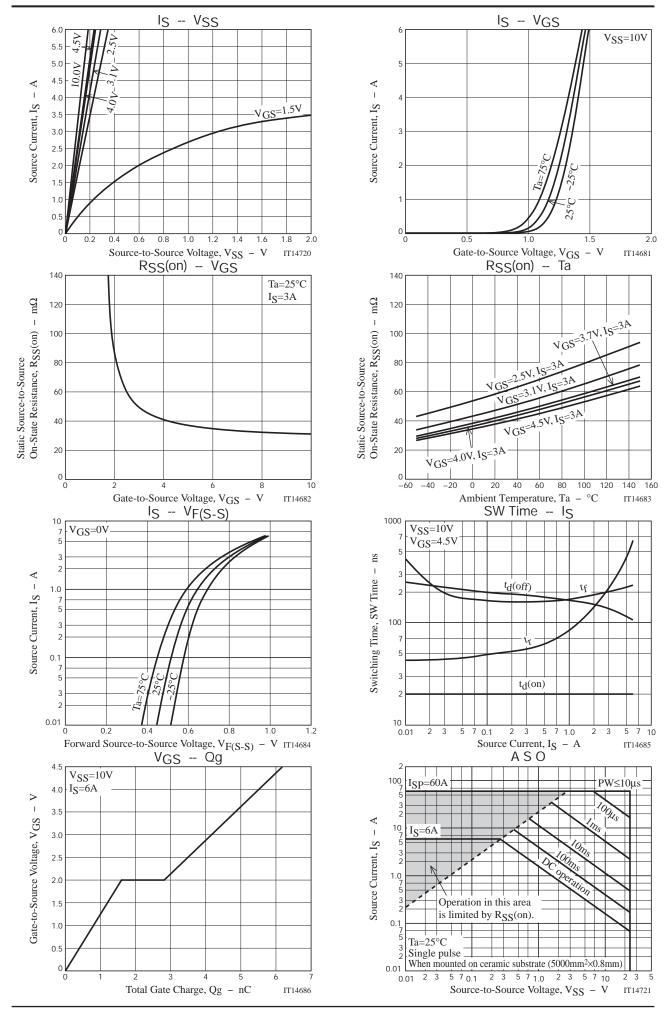


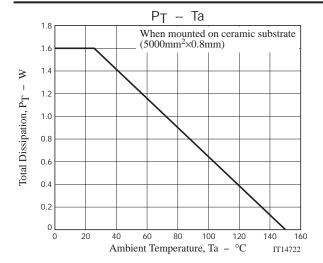
Test Circuit 6

IT11567



* Note: Connect the mesurement terminal reversely if you want to measure the FET2 side.



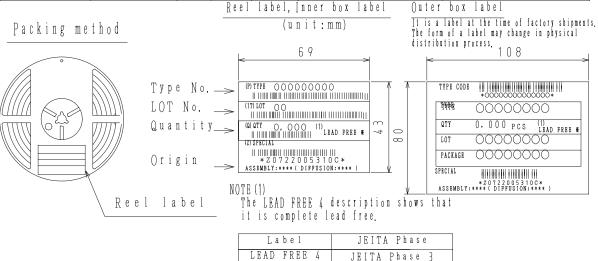


Taping Specification

EFC4612R-TR

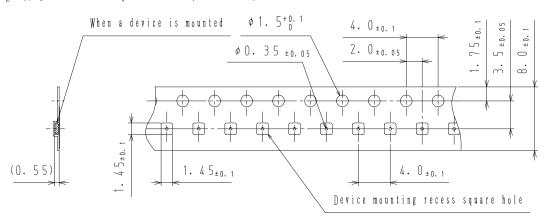
1. Packing Format

Package Name	Carrier Tape	Maximum Number of devices contained (pcs)			Packing format		
	Туре	Reel	Inner box	Outer box	Inner BOX (C-1)	Outer BOX (A-7)	
EFCP1313	145145×055	5,000	25,000	150,000	5 reels contained	6 inner boxes contained	
- 4 C C - 0 3 7					Dimensions:mm (external)	Dimensions:mm (external)	
					183×72×185	4 4 0 × 1 9 5 × 2 1 0	

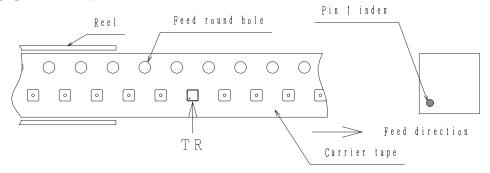


7. Taping configuration

2-1. Carrier tape size (unit:mm)



2-2. Device placement direction

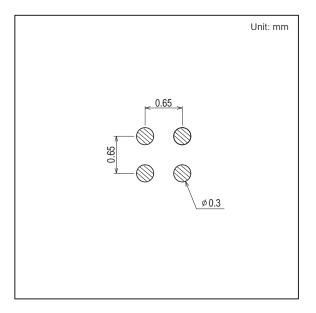


Those with pin 1 index on the opposide of feed hole·····TR

Outline Drawing

EFC4612R-TR

Land Pattern Example



Note on usage: Since the EFC4612R is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

- Any and all SANYO Semiconductor Co.,Ltd. products described or contained herein are, with regard to "standard application", intended for the use as general electronics equipment. The products mentioned herein shall not be intended for use for any "special application" (medical equipment whose purpose is to sustain life, aerospace instrument, nuclear control device, burning appliances, transportation machine, traffic signal system, safety equipment etc.) that shall require extremely high level of reliability and can directly threaten human lives in case of failure or malfunction of the product or may cause harm to human bodies, nor shall they grant any guarantee thereof. If you should intend to use our products for new introduction or other application different from current conditions on the usage of automotive device, communication device, office equipment, industrial equipment etc., please consult with us about usage condition (temperature, operation time etc.) prior to the intended use. If there is no consultation or inquiry before the intended use, our customer shall be solely responsible for the use.
- Specifications of any and all SANYO Semiconductor Co.,Ltd. products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- SANYO Semiconductor Co.,Ltd. assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all SANYO Semiconductor Co.,Ltd. products described or contained herein.
- Regarding monolithic semiconductors, if you should intend to use this IC continuously under high temperature, high current, high voltage, or drastic temperature change, even if it is used within the range of absolute maximum ratings or operating conditions, there is a possibility of decrease reliability. Please contact us for a confirmation
- SANYO Semiconductor Co.,Ltd. strives to supply high-quality high-reliability products, however, any and all semiconductor products fail or malfunction with some probability. It is possible that these probabilistic failures or malfunction could give rise to accidents or events that could endanger human lives, trouble that could give rise to smoke or fire, or accidents that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all SANYO Semiconductor Co.,Ltd. products described or contained herein are controlled under any of applicable local export control laws and regulations, such products may require the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written consent of SANYO Semiconductor Co.,Ltd.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the SANYO Semiconductor Co.,Ltd. product that you intend to use.
- Upon using the technical information or products described herein, neither warranty nor license shall be granted with regard to intellectual property rights or any other rights of SANYO Semiconductor Co.,Ltd. or any third party. SANYO Semiconductor Co.,Ltd. shall not be liable for any claim or suits with regard to a third party's intellectual property rights which has resulted from the use of the technical information and products mentioned above.

This catalog provides information as of October, 2012. Specifications and information herein are subject to change without notice.